

# AUIRLL024N

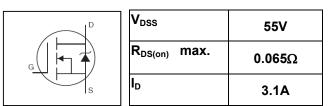
## HEXFET<sup>®</sup> Power MOSFET

## Features

- Advanced Planar Technology
- Low On-Resistance
- Logic Level Gate Drive
- Dynamic dv/dt Rating
- 150°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free, RoHS Compliant
- Automotive Qualified \*

## Description

Specifically designed for Automotive applications, this Cellular design of HEXFET® Power MOSFETs utilizes the latest processing techniques to achieve low on-resistance per silicon area. This benefit combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in Automotive and a wide variety of other applications.





G	D	S
Gate	Drain	Source

Baca part number	Dookogo Typo	Standard Pack		Orderable Part Number
Base part number	Package Type	Form	Quantity	Orderable Part Number
AUIRLL024N	SOT-223	Tape and Reel	2500	AUIRLL024NTR

#### Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Symbol Parameter		Units	
I <sub>D</sub> @ T <sub>A</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V ⑥	4.4		
I <sub>D</sub> @ T <sub>A</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>⑤</sup>	3.1	Α	
I <sub>D</sub> @ T <sub>A</sub> = 70°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>⑤</sup>	2.5	A	
I <sub>DM</sub>	Pulsed Drain Current ①	12		
P <sub>D</sub> @T <sub>A</sub> = 25°C	Maximum Power Dissipation (PCB Mount) 6	2.1	14/	
P <sub>D</sub> @T <sub>A</sub> = 25°C			W	
	Linear Derating Factor (PCB Mount) (S)	8.3	W/°C	
V <sub>GS</sub> Gate-to-Source Voltage		± 16	V	
E <sub>AS</sub> Single Pulse Avalanche Energy (Thermally Limited) <sup>©</sup>		120	mJ	
I <sub>AR</sub>	Avalanche Current ①	3.1	A	
E <sub>AR</sub>	Repetitive Avalanche Energy ①⑤	0.1	mJ	
dv/dt Peak Diode Recovery dv/dt ③		5.0	V/ns	
TJ	· · · · · · · · · · · · · · · · · · ·		°C	
T <sub>STG</sub>	Storage Temperature Range		C	

## Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
$R_{ heta JA}$	Junction-to-Ambient (PCB Mount, steady state) (5)	90	120	°C \\ \
$R_{ heta JA}$	Junction-to-Ambient (PCB Mount, steady state) 6	50	60	°C/W

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\*Qualification standards can be found at <u>www.infineon.com</u>

	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	55			V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250µA
$\Delta V_{(BR)DSS} / \Delta T_J$	Breakdown Voltage Temp. Coefficient		0.048		V/°C	Reference to 25°C, $I_D$ = 1mA
				0.065		V <sub>GS</sub> = 10V, I <sub>D</sub> = 3.1A ④
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance			0.080		V <sub>GS</sub> = 5.0V, I <sub>D</sub> = 2.5A ④
				0.100		V <sub>GS</sub> = 4.0V, I <sub>D</sub> = 1.6A ④
/ <sub>GS(th)</sub>	Gate Threshold Voltage	1.0		2.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
lts	Forward Trans conductance	3.3			S	V <sub>DS</sub> = 25V, I <sub>D</sub> = 1.9A
	Drain-to-Source Leakage Current			25		V <sub>DS</sub> = 55V, V <sub>GS</sub> = 0V
DSS				250	μA	$V_{DS} = 44V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			100	5	V <sub>GS</sub> = 16V
	Gate-to-Source Reverse Leakage			-100	nA	V <sub>GS</sub> = -16V

## Static @ T<sub>1</sub> = 25°C (unless otherwise specified)

# Dynamic Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

•	•	•			
Q <sub>g</sub>	Total Gate Charge	 10.4	15.6		I <sub>D</sub> = 1.9A
$Q_{gs}$	Gate-to-Source Charge	 1.5	2.3	nC	$V_{DS} = 44V$
Q <sub>gd</sub>	Gate-to-Drain Charge	 5.5	8.3		$V_{GS}$ = 5.0V, See Fig 6 and 13 ④
t <sub>d(on)</sub>	Turn-On Delay Time	 7.4			V <sub>DD</sub> = 28V
t <sub>r</sub>	Rise Time	 21			I <sub>D</sub> = 1.9A
t <sub>d(off)</sub>	Turn-Off Delay Time	 18		ns	$R_{G} = 24\Omega$
t <sub>f</sub>	Fall Time	 25			R <sub>D</sub> = 15Ω, See Fig. 10 ④
C <sub>iss</sub>	Input Capacitance	 510			$V_{GS} = 0V$
Coss	Output Capacitance	 140		pF	V <sub>DS</sub> = 25V
C <sub>rss</sub>	Reverse Transfer Capacitance	 58			f = 1.0MHz, See Fig.5
Diode Cha	practeristics				

## **Diode Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
ls	Continuous Source Current (Body Diode)			3.1		MOSFET symbol showing the
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①			12		integral reverse
$V_{SD}$	Diode Forward Voltage			1.0	V	T <sub>J</sub> = 25°C,I <sub>S</sub> = 1.9A,V <sub>GS</sub> = 0V ④
t <sub>rr</sub>	Reverse Recovery Time		39	58	ns	T <sub>J</sub> = 25°C ,I <sub>F</sub> = 1.9A,
Q <sub>rr</sub>	Reverse Recovery Charge		63	94	nC	di/dt = 100A/µs ④
t <sub>on</sub>	Forward Turn-On Time	Intrinsic	turn-or	n time is	negligil	ole (turn-on is dominated by LS+LD)

#### Notes:

① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)

② Starting  $T_J = 25^{\circ}C$ , L = 25mH,  $R_G = 25\Omega$ ,  $I_{AS} = 3.1A$ . (See fig. 12)

④ Pulse width  $\leq$  300µs; duty cycle  $\leq$  2%.

© When mounted on FR-4 board using minimum recommended footprint.

<sup>®</sup> When mounted on 1 inch square copper board, for comparison with other SMD devices.



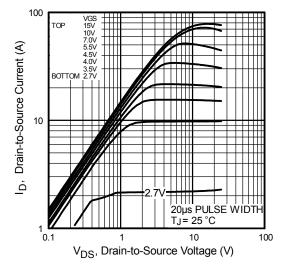


Fig. 1 Typical Output Characteristics

Fig. 2 Typical Output Characteristics

V<sub>DS</sub>, Drain-to-Source Voltage (V)

1

.7V-++

20µs PULSE WIDT TJ= 150°C

100

10

100

ID, Drain-to-Source Current (A)

10

1 **L** 0.1

VGS TOP 15V 10V 7.0V 5.5V 4.5V 4.0V 3.5V BOTTOM 2.7V

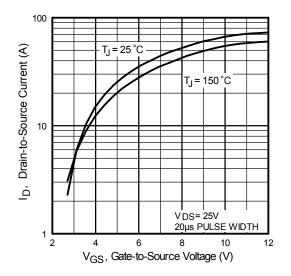


Fig. 3 Typical Transfer Characteristics

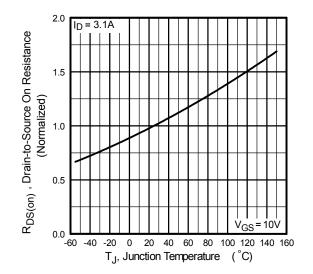


Fig. 4 Normalized On-Resistance vs. Temperature



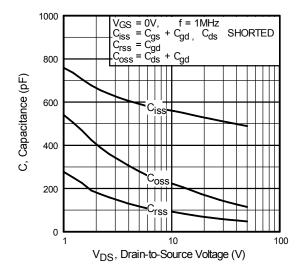


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

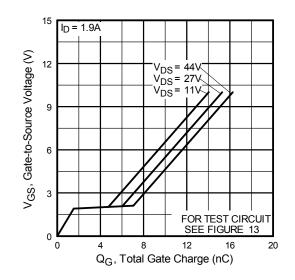


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

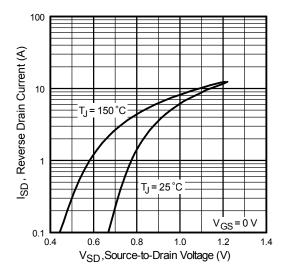


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

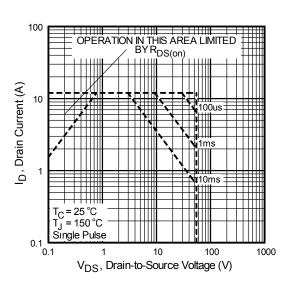
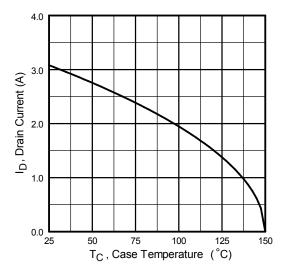
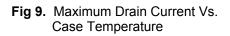


Fig 8. Maximum Safe Operating Area







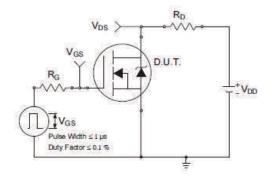


Fig 10a. Switching Time Test Circuit

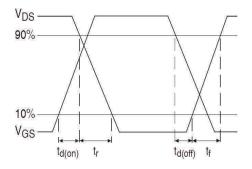


Fig 10b. Switching Time Waveforms

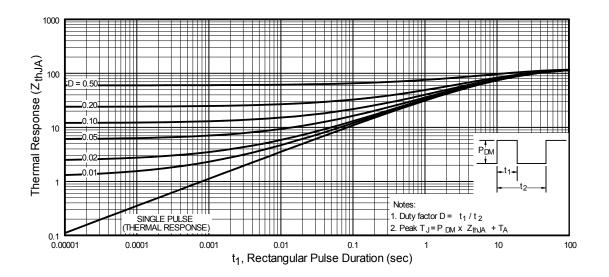


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

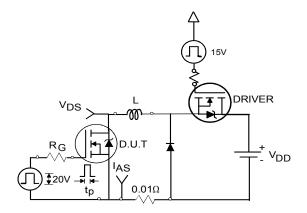


Fig 12a. Unclamped Inductive Test Circuit

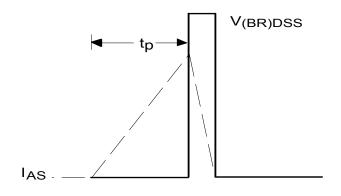


Fig 12b. Unclamped Inductive Waveforms

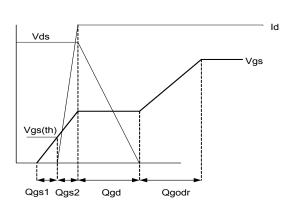


Fig 13a. Basic Gate Charge Waveform

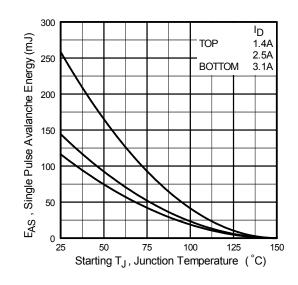


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

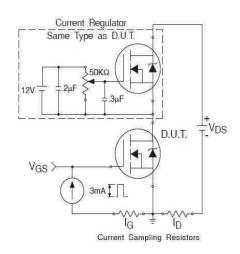
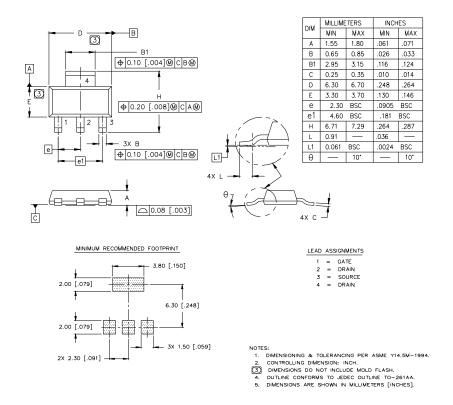


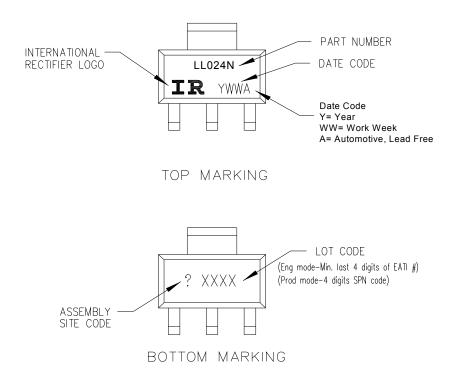
Fig 13b. Gate Charge Test Circuit



# SOT-223 (TO-261AA) Package Outline (Dimensions are shown in millimeters (inches)



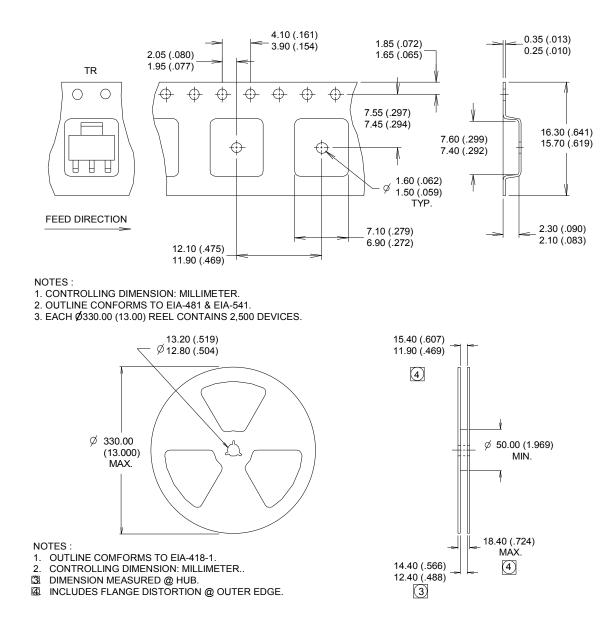
## SOT-223(TO-261AA) Part Marking Information



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



## SOT-223(TO-261AA) Tape and Reel (Dimensions are shown in millimeters (inches)



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



## **Qualification Information**

		Automotive					
			(per AEC-Q101)				
Qualificat	ion Level	Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.					
Moisture	Sensitivity Level	SOT-223	MSL1				
		Class M2 (+/- 150V) <sup>†</sup>					
	Machine Model	AEC-Q101-002					
	Liuman Dadu Madal	Class H1A (+/- 500V) <sup>†</sup>					
ESD	Human Body Model	AEC-Q101-001					
	Charged Device Medal	Class C5 (+/- 2000V) <sup>†</sup>					
	Charged Device Model	AEC-Q101-005					
RoHS Compliant		Yes					

+ Highest passing voltage.

## **Revision History**

Date	Comments						
3/25/2014	<ul> <li>Added "Logic Level Gate Drive" bullet in the features section on page 1</li> <li>Updated part marking on page 7</li> <li>Updated data sheet with new IR corporate template</li> </ul>						
10/29/2015	<ul> <li>Updated datasheet with corporate template</li> <li>Corrected ordering table on page 1.</li> </ul>						

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